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| Notice of References Cited | Application/Control No. 09/608,311 | Applicant(s)/Patent Under Reexamination XIANG ET AL. | |
| | Examiner Paresh Patel | Art Unit 2829 | Page 1 of 1 |

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FOREIGN PATENT DOCUMENTS

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| | W | "Scanning probe microscopy for 2-D semiconductor dopant profiling and device failure analysis" by Henning et al. Thayer School of Engineering, NH, USA |
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.